

Search Notes**Application/Control No.**

10/764,481

Examiner

MARK A. MAIS

**Applicant(s)/Patent under
Reexamination**

HIYAMA ET AL.

Art Unit

2619

SEARCHED

Class	Subclass	Date	Examiner
370	310 328 329	8/18/2008	MAM
	331 338 351		
	352 353		
	389 392		
	401 469		
	474 475 476		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Inventorship Search	6/16/2007	MAM
See Attached Electronic Search	6/16/2007	MAM
See Attached Electronic Search [updated]	3/30/2008	MAM
See Attached Electronic Search [updated]	8/18/2008	MAM